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Application/Control No.	Applicant(s)/Patent under Reexamination
10/542,915	KOCH ET AL.
Examiner	Art Unit
Rita Leykin	2837

SEARCHED			
Class	Subclass	Date	Examiner
318	599	8/18/2006	R.L.
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
USPAT, DERWENT, EPO, JPO, USPGPUB	8/18/2006	R.L.